

**Machine learning clustering techniques for selective mitigation of critical design features**

Lange, Thomas; **Balakrishnan, Aneesh**; Glorieux, Maximilien; Alexandrescu, Dan; Sterpone, Luca Proceedings : 2020 26th IEEE International Symposium on On-Line Testing and Robust System Design : IOLTS 2020, Napoli, Italy, July 13-16, 2020 : virtual edition 2020 / 7 p. : ill <https://doi.org/10.1109/IOLTS50870.2020.9159751>

**Machine learning to tackle the challenges of transient and soft errors in complex circuits**

Lange, Thomas; **Balakrishnan, Aneesh**; Glorieux, Maximilien; Alexandrescu, Dan; Sterpone, Luca 2019 IEEE 25th International Symposium on On-Line Testing and Robust System Design (IOLTS), 1-3 July 2019, Greece 2019 / p. 7-14 : ill <https://doi.org/10.1109/IOLTS.2019.8854423>

**A new FPGA-based detection method for spurious variations in PCBA power distribution network**

**Odintsov, Sergei**; Bozzoli, Ludovica; De Sio, Corrado; Sterpone, Luca; **Jutman, Artur** 2019 22nd International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS), Cluj-Napoca, Romania : proceedings 2019 / 6 p. : ill <https://doi.org/10.1109/DDECS.2019.8724662>

**On the estimation of complex circuits functional failure rate by machine learning techniques**

Lange, Thomas; **Balakrishnan, Aneesh**; Glorieux, Maximilien; Alexandrescu, Dan; Sterpone, Luca 49th Annual IEEE/IFIP International Conference on Dependable Systems and Networks - DSN 2019 : Supplemental Volume : proceedings 2019 / p. 35-41 : ill <https://doi.org/10.1109/DSN-S.2019.00021>